## REQUEST FOR

## CONTINUED EXAMINATION (RCE) TRANSMITTAL

Subsection (b) of 35 U.S.C. § 132, effective on May 29, 2000, provides for continued examination of an utility or plant application filed on or after June 8, 1995.

See The American Inventors Protection Act of 1999 (AIPA).

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Application Number	09/467,992	مسيد
Filing Date	December 20, 1999	
First Named Inventor	Leonard Forbes et al.	
Group Art Unit	2815 - 11 0	-
Examiner Name	Eugene Lee 4/10	
Attorney Docket Number	303.389US2	h) > -

This is a Request for Continued Examination (RCE) under 37 C.F.R. § 1.114 of the above-identified application entitled <u>CIRCUITS WITH A TRENCH CAPACITOR HAVING MICRO-ROUGHENED SEMICONDUCTOR SURFACES</u>.

CIRCUITS WITH A TRENCH CAPACITOR HAVING MICRO-ROUGHENED SEMICONDUCTOR SURFACES.						
Submis	sion required under 37 C.F.R. § 1.114	-1	X	Smil		
1	Consider the amendment(s)/reply under 37 C.F.R. § 1.116 previously filed on	CHN		•		
2	Consider the arguments in the Appeal Brief or Reply Brief previously filed on	0C OC	AUG	REC		
3. <u>X</u>	An Amendment Under 37 CFR § 1.116 (11 pages) is enclosed.	Y CEI	20	RECEIVED		
4	A new power of attorney (_ pages) is enclosed.	NTER	2002	ŒD		
5. <u>X</u>	An Information Disclosure Statement is enclosed (1 page) a. 1 Form(s) 1449 b. 9 Copies of IDS Citations	TECHNOLOGY CENTER 2800		- √ <b>3</b> 		
6. <u>X</u>	A check in the amount of \$740.00 is attached to pay the RCE filing fee required under C.F.R. §	1.17	(e).			
7. <u>X</u>	The Commissioner is hereby authorized to credit overpayments or charge any fees set for 1.16 through 1.18 to Deposit Account No. 19-0743.	th in	37 C.I	F.R. §§		
8	A petition for extension of time in the prior application (_ pages) is enclosed along with a chec to pay the extension fee.	k in t	he amo	ount of <u>\$</u>		
9. <u>X</u>	Other: Clean Version of Pending Claims (7 pages); Clean Version of Amended Specification Red-line Drawing of Figure 1 (1pg); and Formal Drawings as amended (5 pgs.)	Parag	graph (	<u>lpg.);</u>		
	VEGMAN, LUNDBERG, WOESSNER & KLUTH, P.A. Ox 2938, Minneapolis, MN 55402 (612-373-6900)  Atty: Edward J. Brook Reg. No. 40,925	as, Ny	14			
Custo	mer Number 21186					
with suff	CATE UNDER 37 CFR 1.8: The undersigned hereby certifies that this correspondence is being deposited with the Unificient postage as first class mail, in an envelope addressed to: Commissioner for Patents, Box RCE, Washington, D.C. 26th day of August, 2002.  Amu Mor, arb.	20231, ·	es Posta	Il Service		

Signature

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Name

740.00 OP



**EXPEDITED PROCEDURE - EXAMINING GROUP 281** 

IN THE UNITED STATES PATENT AND TRADEMARK OFFICE

Applicant:

Leonard Forbes et al.

Serial No.:

09/467,992

Filed:

December 20, 1999

Title:

CIRCUITS WITH A TRENCH CAPACITOR HAVING MICRO-ROUGHENED SEMICONDUCTOR SURFACES

Examiner: Eugene Lee

Group Art Unit: 2815

Docket: 303.389US2

## AMENDMENT & RESPONSE UNDER 37 C.F.R. § 1.116

Box RCE Commissioner for Patents Washington, D.C. 20231

AMENDMENT & RESPONSE UNDER 37 C.F.R. § 1.116

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In response to the final Office Action mailed May 6, 2002, please amend the appliances: as follows:

## IN THE DRAWINGS

The drawings were objected to under 37 C.F.R. 1.83(a) for failing to show every feature of the invention specified in the claims. The Examiner requested that the trench capacitor formed in a trench and coupled to the "first source/drain region" 106 be shown in FIG. 1 or the feature canceled from the claims.

FIG. 1 has been amended to include a reference number 110' that identifies the "first plate," which is described in the specification on page 6, lines 27-28 as being "integral with" second source/drain region 110.

The Examiner requested the corrected drawing based on his understanding that the first source/drain region 106 is coupled to trench capacitor 119. In fact, it is the second source/drain region 110 that is coupled to the trench capacitor by virtue of the first plate 110' being integral with the second source/drain region 110. The claims have also been amended to make this more clear, as described in greater detail below.

By adding reference number 110' identifying the first plate in FIG. 1, it is easier to see how the trench capacitor is coupled to the second source/drain region 110 of the transistor, i.e., because first plate 110' of the capacitor and the second source/drain region 110 of the transistor 119 constitute the same structure.